



Workshop at ASU

13 November 2025

'Discover Integrated AFM-in-SEM Semiconductor Failure Analysis Flows'

Join us for an **in-person**, interactive workshop at Arizona State University on **integrated semiconductor failure analysis flows**. Discover how **AFM-in-SEM** technology enables comprehensive, correlative in-situ analyses of advanced materials.

Look forward to expert talks and live demonstrations, from insights into Nanoelectronics Metrology & Failure Analysis Lab (ASU) work on semiconductor material behavior, to seeing how correlating mechanical, electrical, and topographical properties benefits your research through in-situ **AFM-in-SEM**.

Venue

Workshop

Arizona State University
501 E Tyler Mall
Tempe, AZ 85281

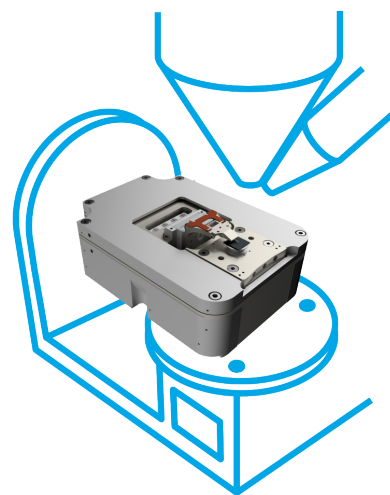
Demo

Arizona State University
Wexler Hall
901 Palm Walk Room 216
Tempe, AZ 85281

Registration

Please note that spots are limited.
Attendance is free of charge.

Register now! →



Speakers



Umberto Celano

Associate Professor
Arizona State University



Jan Neuman

CEO of NenoVision



**Md Ashiqur
Rahman Laskar**

Arizona State University



**Md Jayed
Hossain**

Arizona State University

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Program

09:30 – 10:00	Arrive & morning coffee
10:00 – 10:10	Welcome & Introduction to workshop Speaker: Umberto Celano
10:10 – 10:50	Introducing NenoVision AFM-in-SEM (35 min & Q&A) Speaker: Jan Neuman
10:50 – 11:05	Coffee Break
11:05 – 12:00	Live Demonstration: LiteScope in Action <i>See LiteScope's capabilities live, integrated into a Scanning Electron Microscope (SEM). Understand its unique strengths in correlating mechanical, electrical, and topographical properties</i>
12:00 – 13:00	Lunch <i>Take this opportunity to network with peers, ask questions, and discuss collaborative opportunities</i>
13:00 – 13:20	Introducing the Umberto Celano Group at ASU Speaker: Umberto Celano <i>Umberto Celano will present his research group's activities at ASU, highlighting their focus on understanding semiconductor material behavior through in-situ electron microscopy techniques</i>
13:20 – 13:40	Beyond Classical Limits: Advancing C-AFM with Electron Beam Assistance Speaker: Md Ashiqur Rahman Laskar
13:40 – 14:00	Defect classification in 2D materials using C-AFM and computer vision Speaker: Md Jayed Hossain
14:00 – 14:15	Closing <i>Summary of key takeaways</i>
14:15 – 14:30	Coffee Break
14:30 – 15:30	Interactive Session: Advancing C-AFM with Electron Beam Assistance <i>An interactive demonstration highlighting Advancing C-AFM with Electron Beam Assistance. Engage in a Q&A session with the experts</i>
15:30 – 17:00	1-1 Q&A or demonstrations <i>(Optional & to be booked in advance, limited spaces)</i>